

Prof. Marie-Christine Record

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Reactive phase formation in thin films.

The diffusion couples of interest will be chosen among metal/metal or metal/silicon systems to reveal the quality of thin films formation in the systems Al-Cu, Pt-Si, Mo-Si and W-Si.

Samples for the study were prepared by sputtering technique and analysed by in situ X-ray diffraction analysis, DSC measurement and electrical resistivity measurement to answer questions concerning to composition of phases, their structure and microstructure and kinetics of their formation.

Termín a místo konání:

Čtvrtek, 15.4.2010, 16.30 hod.

Aula MU, Vinařská ul.